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Application Number	10/600,224				
Filing Date	6/20/2003				
First Named Inventor	Bickford, Randall L.	_			
Group Art Unit	2121				
Examiner Name	Not yet Assigned	_			
Attorney Docket Number	23404-cpa				

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<sup>&</sup>lt;sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WiPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WiPO Standard ST. 16 if possible. <sup>8</sup> Applicant is to place a check mark here if English language Translation is attached.



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Complete if Known Substitute for form 1449B/PTO **Application Number** INFORMATION DISCLOSURE Filing Date Bickford, Randall L. **First Named Inventor** STATEMENT BY APPLICANT Group Art Unit **Examiner Name** 

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of 6 **Attorney Docket Number** Sheet 23404-cpa

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Examiner nitiats*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	ŀ
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Application Number		
filing Date		
irst Named Inventor	Bickford, Randall L.	
Group Art Unit		
Examiner Name		
Attorney Docket Number	23404-cna	

			OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
Examin Initials		Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T2
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Examiner Signature Romail Kafil Co	ate onsidered	26/9

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